

IEW2022

<https://web.umons.ac.be/lpmo/en/workshop-iew2022/>

When?

September 12 - 14,
2022

Where?

Mons University

iew2022@umons.ac.be

First International Workshop on Imaging Ellipsometry

Important Dates:

20th of July:

Registration opening day

20th of July:

Abstract submission opening day

15th of August 2022:

Deadline for early bird registration

2nd of September 2022: Deadline
for abstract submission

8th of September 2022:

Deadline for registration

Registration fees:

Early bird

Regular attendee 100,00 €

Students attendee 80,00 €

After 15th of August, 2022

Regular attendee 120,00 €

Students attendee 100,00 €

Optional gala dinner 65,00 €

(accompanying person: 65,00 €)

After the postponement due to the pandemic, live and in person...

The first international workshop on Imaging Ellipsometry (IEW2022) aims at providing a forum for scientists and engineers working in instrumentation and applications of Imaging Ellipsometry (IE) and related techniques.

IEW2022 is a joint organisation of **UMONS** (Prof. M. Voué, Materials Research Institute, LPMO) and UCLouvain (Prof. A. Jonas, IMCN). In order to maximize the interactions, four sessions will be scheduled on a serial scheme to cover:

- **Optical properties of 2D materials**
- **Bioactive coatings and biointerfaces**
- **Functional organic layers for applications in electronics, optics and energy**
- **Hybrid and composite materials**

IEW2022 will gather international participants whose common point is the use of IE or of one of its variants in materials science, biointerfaces, ...

Both young and experienced researchers are encouraged to participate and to interact on the basis of a common experimental technique applied to different fields, sharing common experimental issues.

We hope to meet you in Mons to share an experience centered on an experimental technique of optical characterization in full expansion.